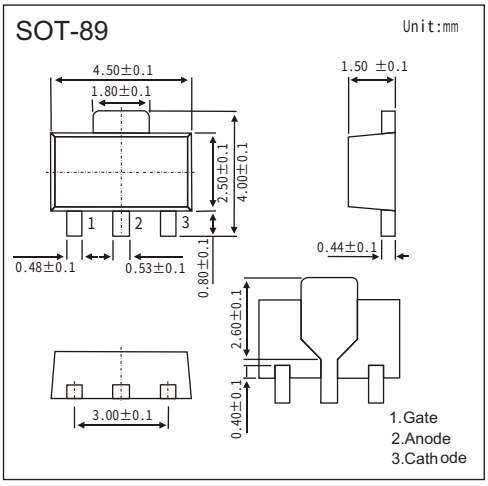
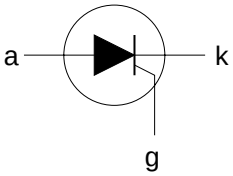
Silicon Controlled Rectifiers

BT169-400

■ Features

- Blocking voltage to 400 V
- Average on-state current to 0.5 A
- General purpose switching





■ Absolute Maximum Ratings Ta = 25℃

Parameter	Symbol	Rating	Unit
Repetitive peak off-state voltages	V_{DRM},V_{RRM}	400	V
Average on-state current	$I_{T(AV)}$	0.5	A
RMS on-state current	$I_{T(RMS)}$	0.8	A
Non-repetitive peak on-state current	I_{TSM}	8	A

■ Electrical Characteristics Ta = 25℃

Parameter	Symbol	Test conditions		Min	Typ	Max	Unit
Repetitive peak off-state voltages	V_{DRM}			400			V
Average on-state current	$I_{T(AV)}$	Half sine wave;Tlead≤ 83 ℃				0.5	A
RMS on-state current	$I_{T(RMS)}$	All conduction angles				0.8	A
Non-repetitive peak on-state current	I_{TSM}	full sine wave;	t = 10 ms			8	A
		Tj = 25℃ prior to surge	t = 8.3 ms			9	A
I^2t for fusing	I^2t	t = 10 ms				0.32	A^2S
Repetitive rate of rise of on-state current after triggering	dI_T/dt	I_{TM} = 2 A; I_G = 10m A; dI_G/dt = 100m A/μs				50	A/μs
Peak gate current	I_{GM}					1	A
Peak gate voltage	V_{GM}					5	V
Peak gate power	P_{GM}					2	W
Average gate power	$P_{G(AV)}$	over any 20 ms period				0.1	W
Thermal resistance junction to ambient	$R_{\theta JA}$	PCB mounted,lead length=4mm			150		K/W
Storage temperature	T_{stg}			-40		150	℃
Operating junction temperature	T_j					125	℃

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■ Electrical Characteristics Ta = 25℃

Parameter	Symbol	Test conditions	Min	Typ	Max	Unit
Gate trigger current	I_{GT}	V_D = 12 V; I_T = 10m A,gate open circuit		50	200	μA
Latching current	I_L	V_D = 12 V; I_{GT} = 0.5mA R_{GK}=1KΩ		2	6	mA
Holding current	I_H	V_D = 12 V; I_{GT} = 0.5mA R_{GK}=1KΩ		2	5	
On-state voltage	V_T	I_T = 1 A		1.2	1.35	V
Gate trigger voltage	V_{GT}	V_D = 12 V; I_T = 10mA,gate open circuit		0.5	0.8	V
		V_D = $V_{DRM(max)}$; I_T = 10mA; Tj = 125 ℃	0.2	0.3		V
Off-state leakage current	I_D,I_R	V_D = $V_{DRM(max)}$;V_R=$V_{RRM(max)}$ Tj = 125 ℃ R_{GK}=1KΩ		0.05	0.1	mA
Critical rate of rise of off-state voltage	dV_D/dt	V_{DM} =67% $V_{DRM(max)}$; Tj = 125℃; exponential R_{GK}=1KΩ		25		V/μS
Gate controlled turn-on time	t_{gt}	I_{TM}=2A;V_D=$V_{DRM(max)}$; I_G=10mA dI_G/dt = 0.1 A/μs		2		μS
Circuit commutated turn-off time	t_q	I_{TM} = 1.6 A; V_D = 67%$V_{DRM(max)}$; Tj=125℃;V_R=35V;R_{GK}=1kΩ dI_{TM}/dt = 30 A/μs;V_D/dt = 2V/μs		100		μS

■ Marking

Marking	BT169-400

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■ Typical Characteristics

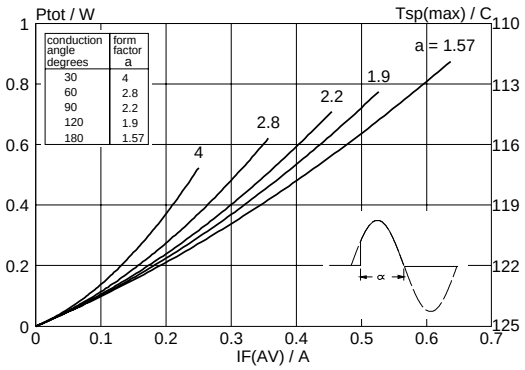

Fig.1. Maximum on-state dissipation, P_{tot}, versus average on-state current, $I_{T(AV)}$, where a = form factor = $I_{T(RMS)}$ / $I_{T(AV)}$.

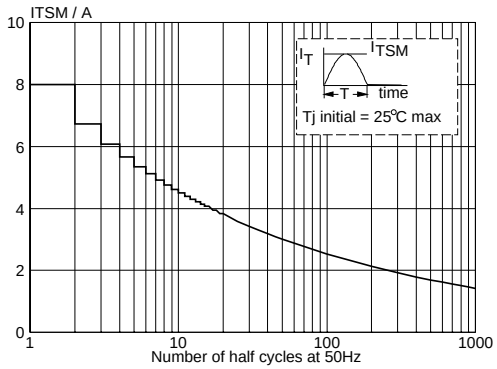

Fig.4. Maximum permissible non-repetitive peak on-state current I_{TSM}, versus number of cycles, for sinusoidal currents, f = 50 Hz.

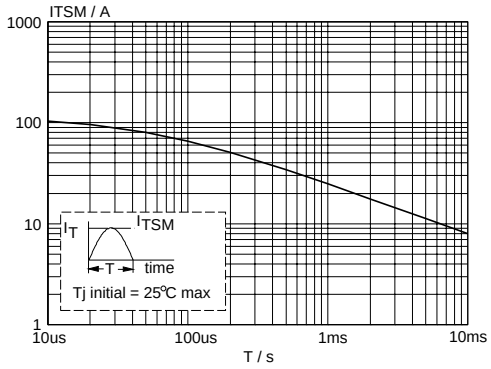

Fig.2. Maximum permissible non-repetitive peak on-state current I_{TSM}, versus pulse width t_p, for sinusoidal currents, $t_p \leq 10ms$.

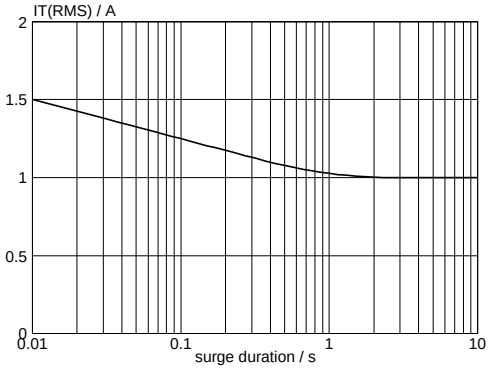

Fig.5. Maximum permissible repetitive rms on-state current $I_{T(RMS)}$, versus surge duration, for sinusoidal currents, f = 50 Hz; $T_{sp} \leq 112^{\circ}C$.

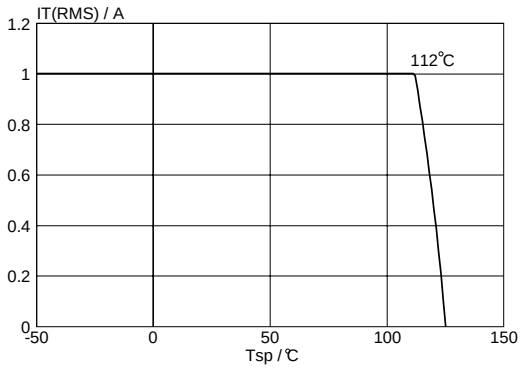

Fig.3. Maximum permissible rms current $I_{T(RMS)}$, versus solder point temperature T_{sp}.

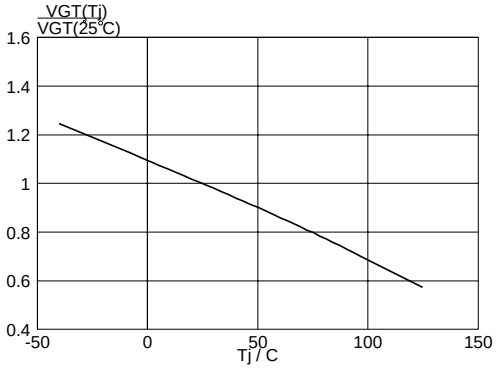

Fig.6. Normalised gate trigger voltage $V_{GT}(T_j)$/ $V_{GT}(25^{\circ}C)$, versus junction temperature T_j.

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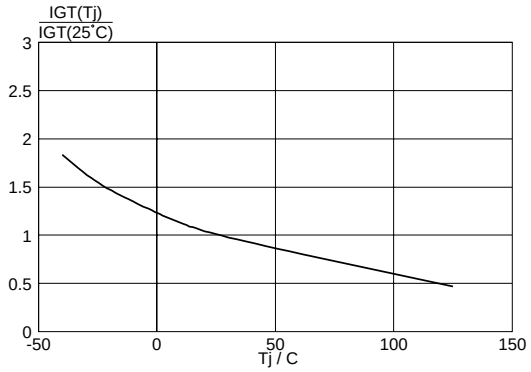

Fig.7. Normalised gate trigger current $I_{GT}(T_j)/ I_{GT}(25^{\circ}C)$, versus junction temperature T_j.

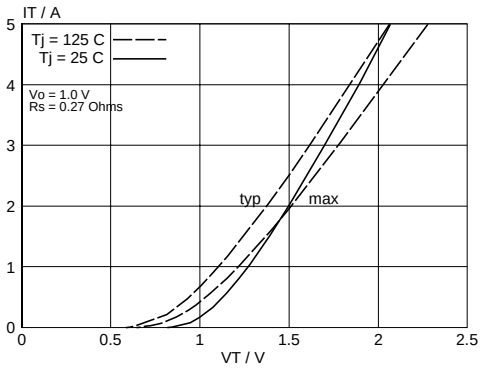

Fig.10. Typical and maximum on-state characteristic.

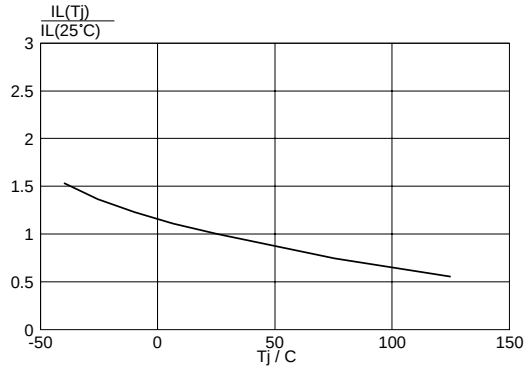

Fig.8. Normalised latching current $I_L(T_j)/ I_L(25^{\circ}C)$, versus junction temperature T_j, R_{GK} = 1 kΩ.

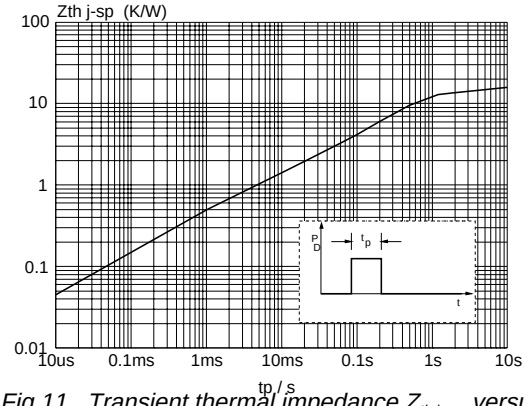

Fig.11. Transient thermal impedance $Z_{th\ j\text{-}sp}$, versus pulse width t_p.

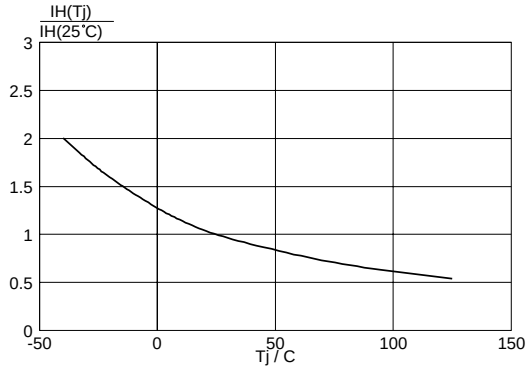

Fig.9. Normalised holding current $I_H(T_j)/ I_H(25^{\circ}C)$, versus junction temperature T_j, R_{GK} = 1 kΩ.

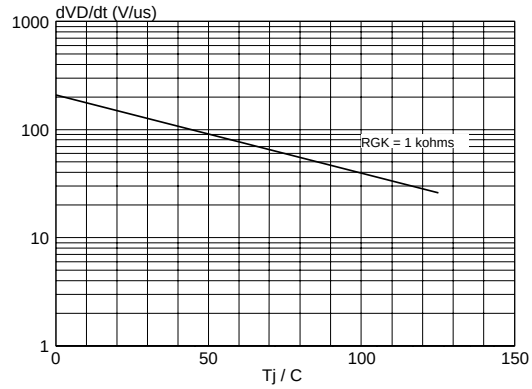

Fig.12. Typical, critical rate of rise of off-state voltage, dV_D/dt versus junction temperature T_j.